Symbols and Abbreviations

A	limiting availiability
$A(t)$	pointwise availability
CAS	current adjustment subsystem
CCF	common mode (cause) failure
Δt_w	repair time window
δ_{jk}	Kronecker's delta function
$D(t)$	down time
DCL	dormant closed line
DCT	dual - coupled triode subsystem
DIV	divider
DOL	dormant opened line
$E[X]$	mathematical expectation of the random variable X
FSP	fast scram pentode subsystem
FSS	fast scram subsystem
FST	fast scram triode subsystem
$F(t)$	cumulative failure probability
$f(t)$	cumulative failure probability density (or distribution)
$\phi(\mathbf{X}(t))$	structure function of the random vector $\mathbf{X}(t)$
$I_{\phi(j)}$	structural importance of component j
$IMP_S(j)$	reliability importance of component j
IMP_{FV}	Fussell - Vesely importance
IMP_{BB}	Birnbaum importance
IMP_{BP}	Balrow - Proschan importance
κ	coefficient of variation
$\lambda(t)$	failure (or hazard) rate
$\lambda^*(t)$	common - failure rate
$\lambda(j \to k)$	transition rate, usually failure transition rate
$L_{(\mu,\sigma)}(x)$	Log - normal distribution
$\mu(t)$	repair rate
$\mu(j \to k)$	repair transition rate

M	transition matrix
MRY	master relay subsystem
MTTF	mean time to failure
MTBF	mean time between failures
MTTR	mean time to repair
MTBR	mean time between repairs
MTTFF	mean time to first failure
MTTFR	mean time to first repair
$\mathrm{N}_{(\mu,\sigma)}(x)$	Gaussian (normal) distribution
$\pi(S),\ \wp(S)$	partition of the event S
$P(A),\ \Pr(A)$	probability of the event A
$\Pr(A|B)$	probability of A given B
Q	limiting unavailability
$Q(t)$	pointwise unavailability
$R(t)$	reliability
RY[14]	relay unit
SDA	scram level definition and activation subsystem
SRY	slave relay subsystem
SSS	slow scram subsystem
SST	slow scram triode subsystem
τ	inspection time, or time parameter
$U(t)$	pointwise unreliability, up time
UIC	uncompensated ionizing chamber unit
V[3]	pentode unit
$\varpi(t_1,t_2)$	interval failure frequency
ϖ	failure frequency